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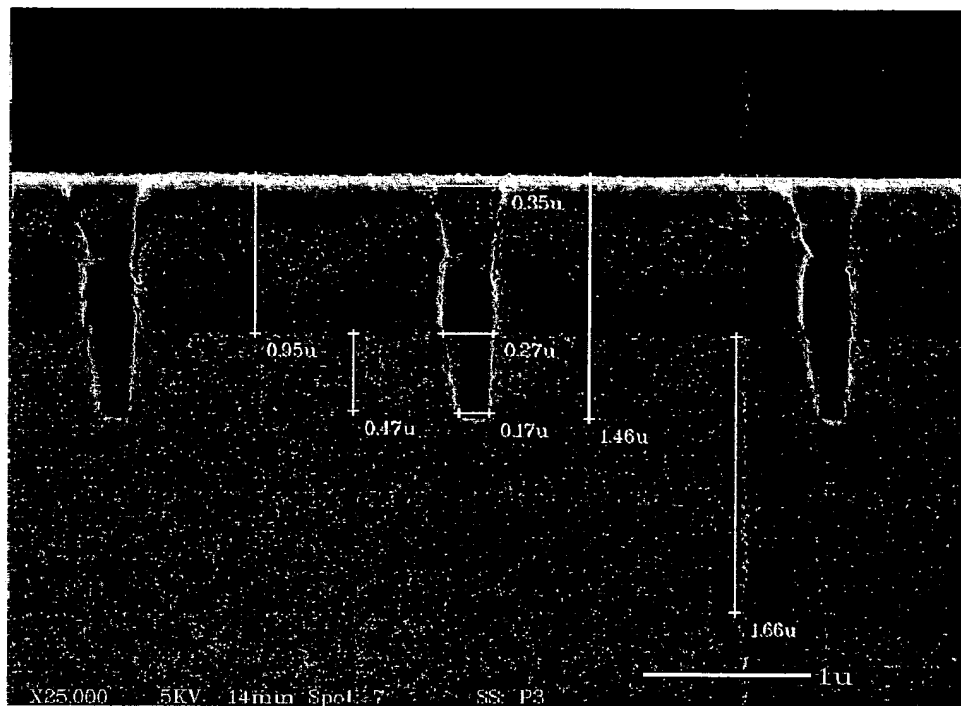
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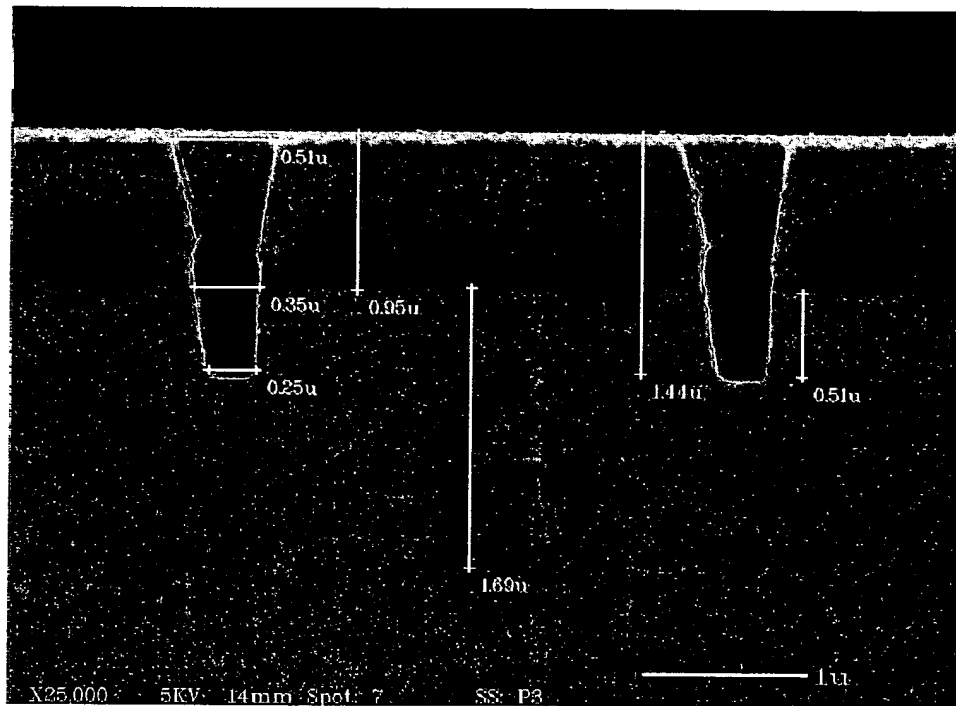
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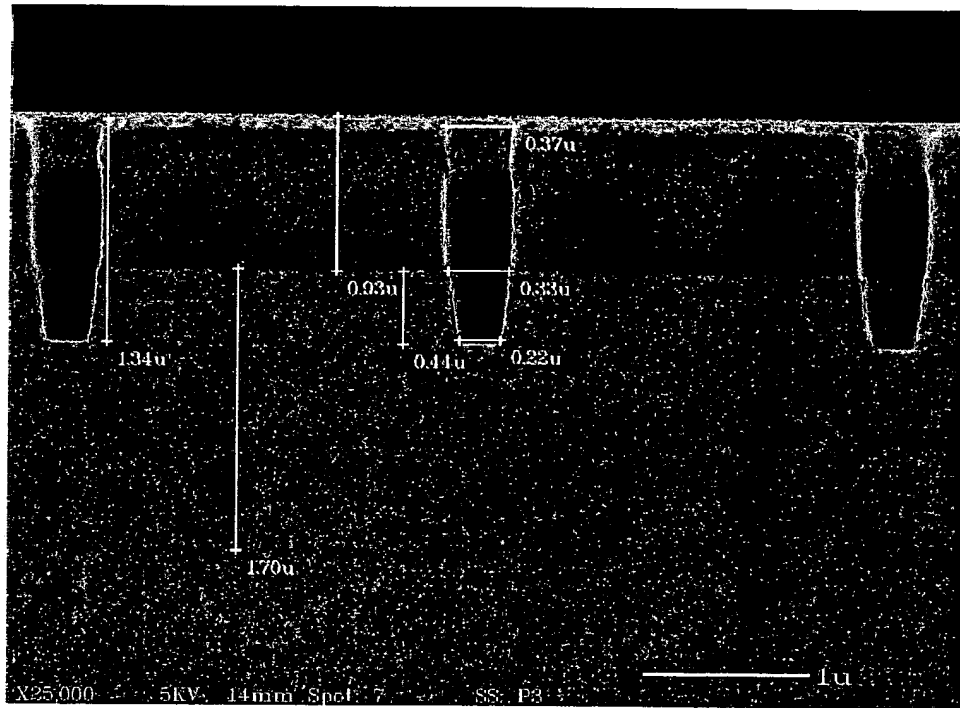
SEM image of 0.35 micron via etch with FTM/C₄F₆/Ar plasma

Figure 3



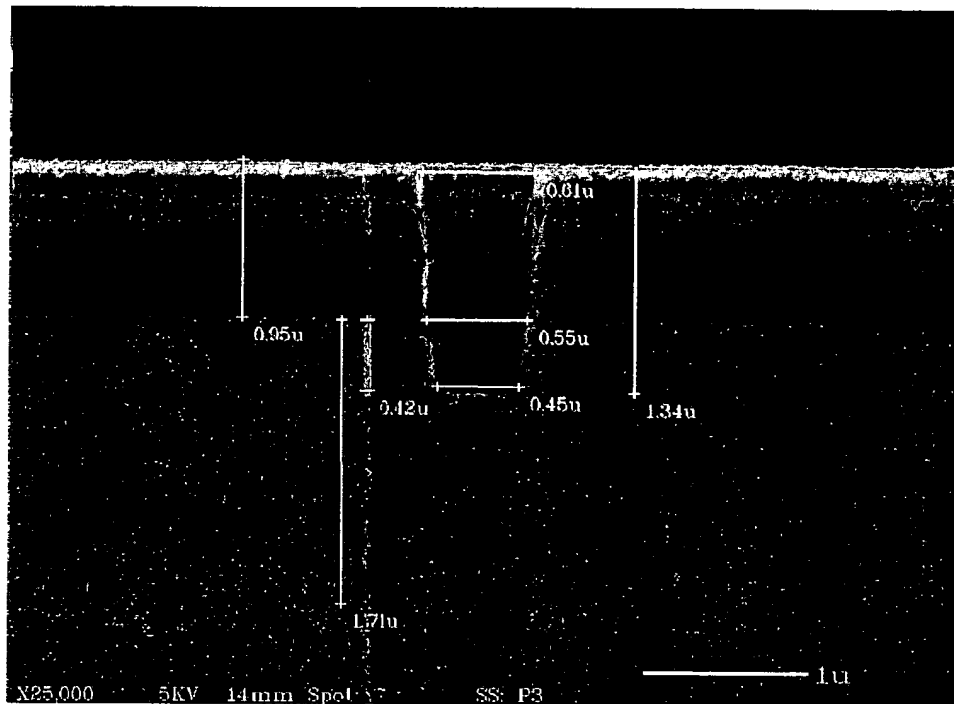
SEM image of 0.50 micron via etch with FTM/C₄F₆/Ar plasma

Figure 4



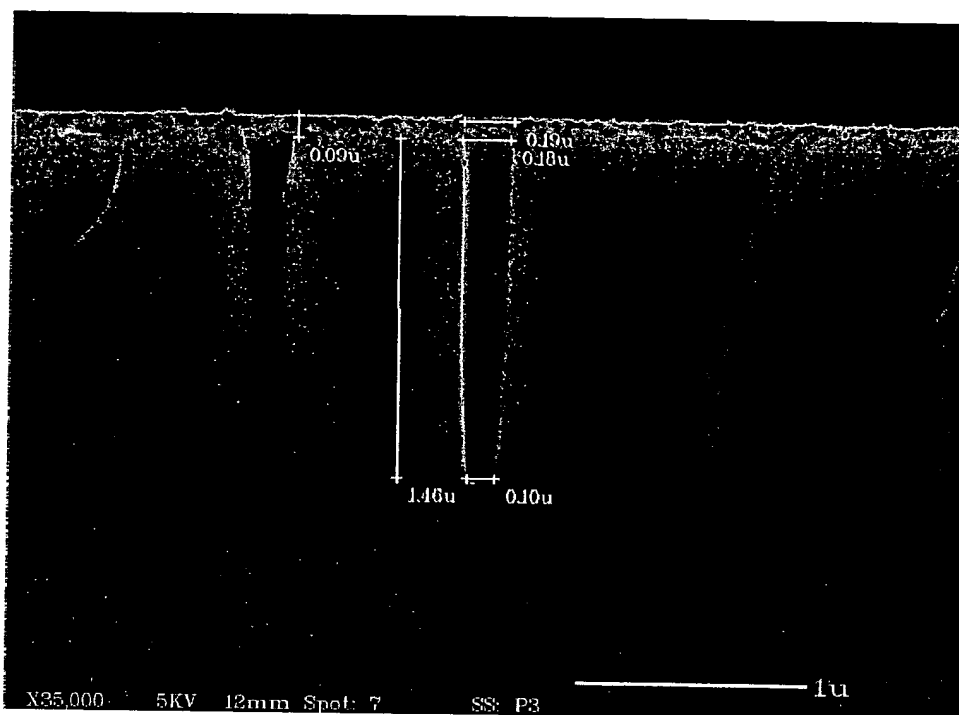
SEM image of 0.35 micron via etch with $O_2/C_4F_6/Ar$ plasma

Figure 5



SEM image of 0.50 micron via etch with $O_2/C_4F_6/Ar$ plasma

Figure 6



SEM image of 0.30 micron via etch with FTM/C₄F₆/Ar Mixture

Figure 7



Appl. No. 10/619,922
Amdt. Dated May 14, 2004
Reply to Notice of Missing Parts of
Oct. 15, 2003
Replacement Sheet 1 of 6

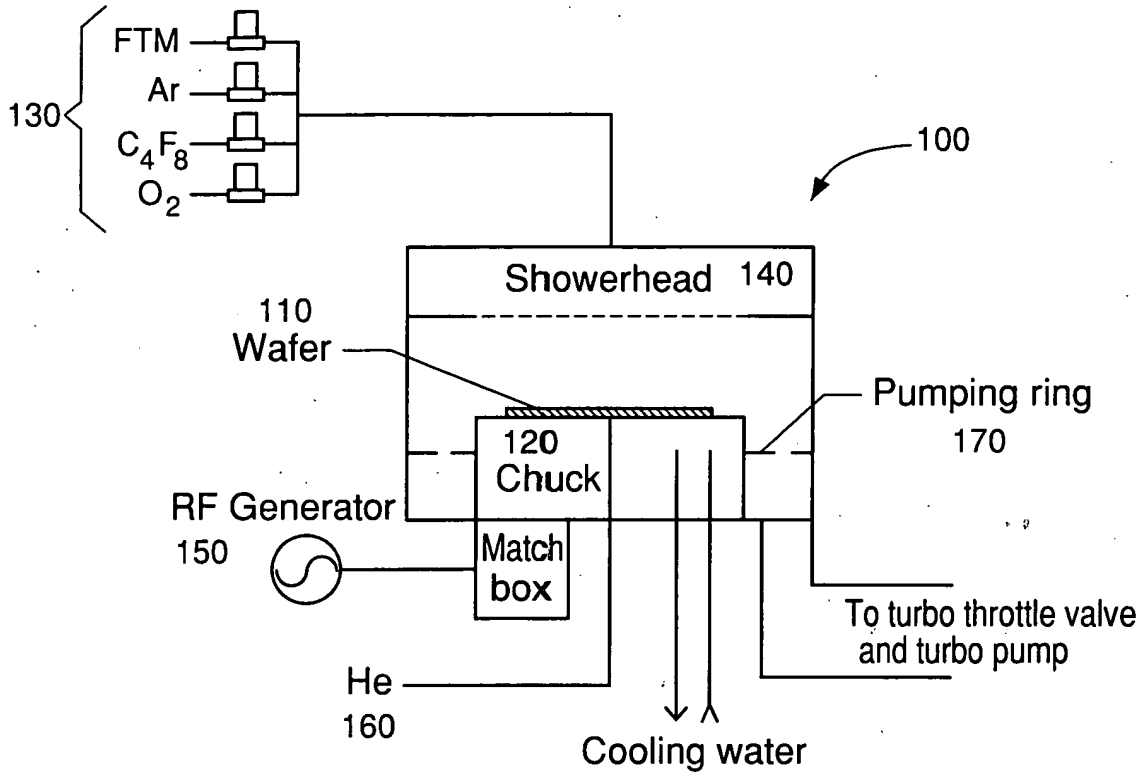


Figure 1

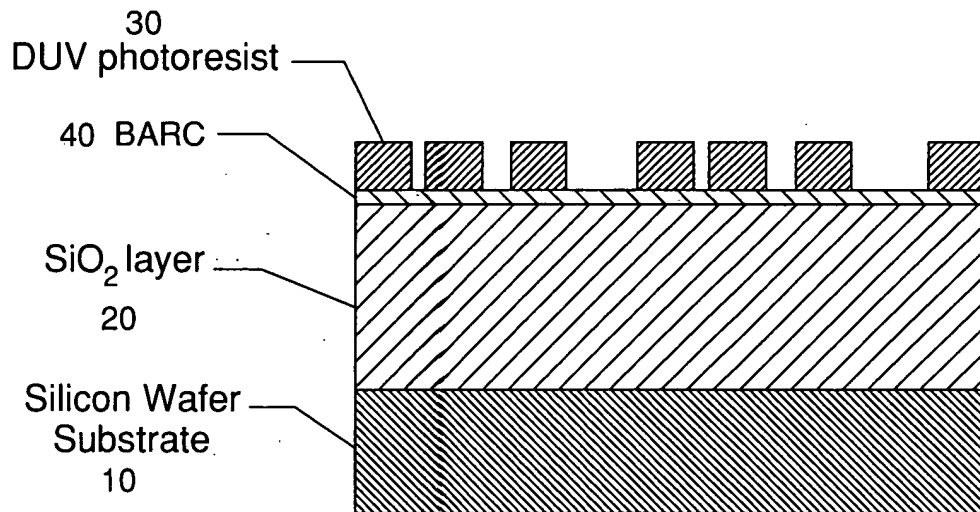


Figure 2